## WHAT IS CLAIMED IS:

10

15

1. A data storage and retrieval medium, comprising:

a data layer capable of storing and erasing data via application of an energy beam; and

a separate capping layer deposited on said data layer, said separate capping layer being relatively transparent to said energy beam and comprising at least one material from a group comprising:

an epitaxial material;

an electrically conducting material;

a robust high melting point material; and

the robust high melting point material combined with a thin dielectric layer.

- 2. The data storage and retrieval medium of claim 1, wherein said epitaxial layer comprises an epitaxial material having an ability to grow in single-crystal form on Silicon 111 (Si(111)).
  - 3. The data storage and retrieval medium of claim 2, wherein the epitaxial material is calcium fluoride.
  - 4. The data storage and retrieval media of claim 1, wherein the electrically conducting material comprises graphite.
- 5. The data storage and retrieval medium of claim 1, wherein the electrically conducting material comprises carbon.

- 6. The data storage and retrieval medium of claim 1, wherein the energy beam comprises a near field optical non-diffraction limited electron beam.
- 7. The data storage and retrieval medium of claim 1, wherein the energy beam comprises an electron beam.
- 5 8. The data storage and retrieval medium of claim 1, wherein the robust high melting point material comprises Mo.
  - A data storage and retrieval medium, comprising:
     an alterable data layer having the ability to be altered by an energy beam; and
- a separate capping layer deposited atop the data layer, the separate capping layer

  being relatively transparent to the energy beam and comprising at least one material from
  a group comprising:

a robust high melting point material; an electrically conductive material; and

an epitaxial material.

15

- 10. The data storage and retrieval medium device of claim 9, wherein said robust high melting point material comprises molybdenum.
- 11. The data storage and retrieval medium device of claim 9, wherein said energy beam comprises a near-field optical non-diffraction limited beam.
- 20 12. The data storage and retrieval media device of claim 9, wherein said epitaxial material comprises calcium fluoride.

5

- 13. The data storage and retrieval media device of claim 9, wherein said electrically conductive material comprises a conducting polycrystalline or amorphous capping material.
- 14. The data storage and retrieval media device of claim 13, wherein said conducting polycrystalline or amorphous capping material comprises at least one from a group comprising graphite and graphitic (sp<sup>2</sup>-bonded) amorphous carbon.
  - 15. The data storage and retrieval media device of claim 9, wherein said data layer comprises InSe.
- 16. The data storage and retrieval media device of claim 9, wherein said energy beam comprises an electron beam.
  - 17. The data storage and retrieval media device of claim 16, wherein said group of materials further comprises at least one from a group comprising GaSe, WSe<sub>2</sub>, MoS<sub>2</sub>, MoTe<sub>2</sub>, GaS, and InS.
- 18. The data storage and retrieval media device of claim 9, wherein said group of materials further comprises:

the robust high melting point material and a thin dielectric layer.

- 19. The data storage and retrieval media device of claim 18, wherein said robust high melting point material comprises molybdenum, and said thin dielectric layer comprises silicon oxide.
- 20. A method for fabricating data storage and retrieval media, comprising:

  providing a data layer capable of alteration via application of an energy beam; and

15

depositing a capping layer upon said data layer, said capping layer being relatively transparent to the energy beam and comprising at least one material from a group comprising:

a robust high melting point material;

an electrically conductive material; a highly anisotropic layered material; and

an epitaxial material.

- 21. The method of claim 20, wherein said robust high melting point material comprises molybdenum.
- 10 22. The method of claim 20, wherein said low mass density material comprises an epitaxial material.
  - 23. The method of claim 22, wherein said epitaxial material comprises calcium fluoride.
  - 24. The method of claim 20, wherein said electrically conductive material comprises one from a group comprising a conducting polycrystalline material and a conducting amorphous material.
    - 25. The method of claim 24, wherein said conducting polycrystalline or amorphous capping material comprises at least one from a group comprising graphite and amorphous carbon.
- 26. The method of claim 20, wherein said data layer comprises InSe.
  - 27. The method of claim 20, wherein said energy beam comprises a near-field optical non-diffraction limited beam.

- 28. The method of claim 20, wherein said highly anisotropic layered material comprises at least one from a group comprising GaSe, WSe<sub>2</sub>, MoS<sub>2</sub>, MoTe<sub>2</sub>, GaS, and InS.
- 29. The method of claim 20, wherein said group of materials further 5 comprises:

molybdenum and a thin dielectric layer.

- 30. The method of claim 29, wherein said thin dielectric layer comprises silicon oxide.
  - 31. A method for fabricating data storage and retrieval media, comprising: providing a data layer alterable via application of an energy beam; and

depositing a capping layer upon said data layer, said capping layer being relatively transparent to the energy beam and comprising at least one material from a group comprising:

an epitaxial material;

15 a conducting material;

10

a highly anisotropic layered material;

a robust high melting point material; and

the robust high melting point material combined with a dielectric layer.

32. The method of claim 31, wherein said epitaxial layer comprises an epitaxial material having an ability to grow in single-crystal form on Silicon 111 (Si(111)).

- 33. The method of claim 32, wherein the epitaxial material comprises calcium fluoride.
- 34. The method of claim 31, wherein the conducting material comprises graphite.
- 5 35. The method of claim 31, wherein the conducting material comprises sp<sup>2</sup>-bonded carbon.
  - 36. The method of claim 31, wherein the highly anisotropic layered material comprises a layered chalcogenide.
- 37. The method of claim 31, wherein the highly anisotropic layered material comprises one from a group comprising graphite, GaSe, WSe<sub>2</sub>, MoS<sub>2</sub>, MoTe<sub>2</sub>, GaS, and InS.
  - 38. The method of claim 31, wherein said robust high melting point material comprises molybdenum.
- 39. The method of claim 38, wherein said dielectric layer comprises silicon oxide.